

Si6435DQ

30V P-Channel PowerTrench® MOSFET

General Description

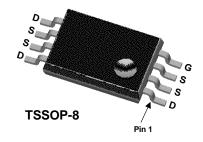
This P-Channel MOSFET is a rugged gate version of Fairchild Semiconductor's advanced PowerTrench process. It has been optimized for power management applications requiring a wide range of gate drive voltage ratings (4.5V-20V).

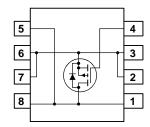
Applications

- · Battery protection
- DC/DC conversion
- · Power management
- Load switch

Features

- -4.5 A, -30 V $R_{DS(ON)} = 40 \text{ m}\Omega$ @ $V_{GS} = -10 \text{ V}$ $R_{DS(ON)} = 70 \text{ m}\Omega$ @ $V_{GS} = -4.5 \text{ V}$
- $\bullet~$ Extended V_{GSS} range (±20V) for battery applications
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS(ON)}}$
- Low profile TSSOP-8 package





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V_{DSS}	Drain-Source Voltage		-30	V
V_{GSS}	Gate-Source Voltage		± 20	V
I _D	Drain Current - Continuous	(Note 1)	-4.5	А
	- Pulsed		-30	
P_D	Power Dissipation	(Note 1a)	1.3	W
		(Note 1b)	0.6	
T_J, T_{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	87	°C/W
		(Note 1b)	114	

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
6435 Si6435DQ		13"	16mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	racteristics	I		1		
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-30			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = -250 \mu\text{A}$, Referenced to 25°C		-23		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-1	-1.7	-3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu\text{A}$, Referenced to 25°C		5		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$\begin{split} V_{GS} &= -10 \text{ V}, I_D = -4.5 \text{ A} \\ V_{GS} &= -4.5 \text{ V}, I_D = -3.4 \text{ A} \\ V_{GS} &= -10 \text{ V}, I_D = -4.5 \text{A}, T_J = 125^{\circ} \text{C} \end{split}$		27 42 38	40 70 60	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = -10 \text{ V}, V_{DS} = -5 \text{ V}$	-30			Α
g _{FS}	Forward Transconductance	$V_{DS} = -15 \text{ V}, I_{D} = -4.5 \text{ A}$		12		S
Dvnamio	Characteristics	•		•		
C _{iss}	Input Capacitance	$V_{DS} = -15 \text{ V}. V_{GS} = 0 \text{ V}.$		854		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		215		pF
C _{rss}	Reverse Transfer Capacitance	7		112		pF
Switchin	g Characteristics (Note 2)	1	ı		1	
t _{d(on)}	Turn-On Delay Time	$V_{DD} = -15 \text{ V}, I_{D} = -1 \text{ A},$		9	20	ns
t _r	Turn-On Rise Time	$V_{GS} = -10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		14	20	ns
t _{d(off)}	Turn-Off Delay Time	7		29	55	ns
t _f	Turn-Off Fall Time			15	25	ns
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_F = -1.25 \text{ A},$ $dI_F/dt = 100\text{A}/\mu\text{s}$		19	80	ns
Qg	Total Gate Charge	$V_{DS} = -15 \text{ V}, I_{D} = -4.5 \text{ A},$		15	35	nC
Q _{gs}	Gate-Source Charge	V _{GS} = −10 V		2.4		nC
Q_{gd}	Gate-Drain Charge			3		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source				-1.25	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -1.25 \text{ A (Note 2)}$		-0.75	-1.2	V

Notes

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^{1.} R_{QJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{QJC} is guaranteed by design while R_{QCA} is determined by the user's board design.

a) $\rm R_{\rm \theta JA}$ is 87 °C/W (steady state) when mounted on a 1 inch² copper pad on FR-4.

b) $R_{\theta JA}^{-}$ is 114 °C/W (steady state) when mounted on a minimum copper pad on FR-4.

^{2.} Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

Typical Characteristics

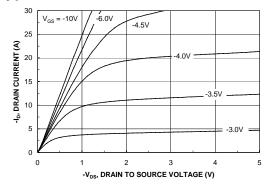


Figure 1. On-Region Characteristics.

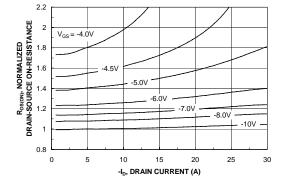


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

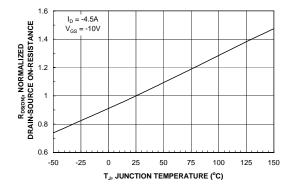


Figure 3. On-Resistance Variation with Temperature.

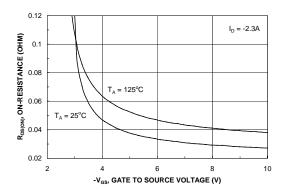


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

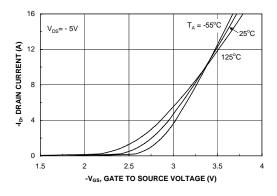


Figure 5. Transfer Characteristics.

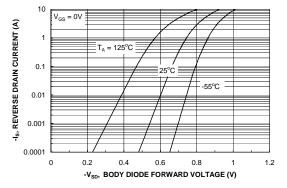


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics

100

10

0.1

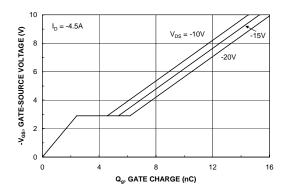
0.01

0.1

V_{GS} = -10V SINGLE PULSE

 $R_{\theta JA} = 114^{\circ}\text{C/W}$ $T_A = 25^{\circ}\text{C}$

DRAIN CURRENT (A)



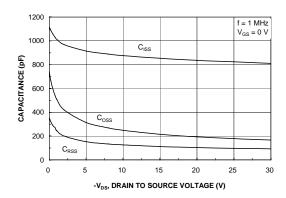


Figure 7. Gate Charge Characteristics.



Figure 8. Capacitance Characteristics.

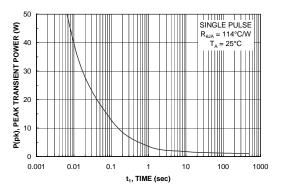


Figure 9. Maximum Safe Operating Area.

-V_{DS}, DRAIN-SOURCE VOLTAGE (V)

10



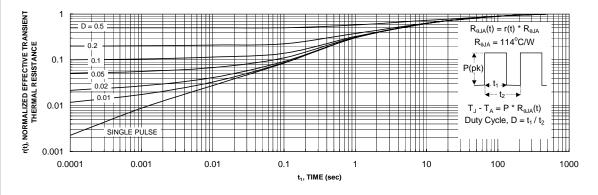


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

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